

Search Notes

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Examiner

Sharon Hurt

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

1648

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EDAN: Invventor Search: Young-Min Lee, Sangilm Yun, Seung Lee	8/21/2007	SH
STIC: Sequence search: SEQ ID NO: 45	9/4/2007	SH
PUBMED: see attached	8/21/2007	SH
EAST: see attached	8/28/2007	SH
PUBMED: see attached	8/28/2007	SH
PUBMED: see attached	9/4/2007	SH